

UNISONIC TECHNOLOGIES CO., LTD

14N65K-MT **Preliminary Power MOSFET**

14A, 650V N-CHANNEL POWER MOSFET

DESCRIPTION

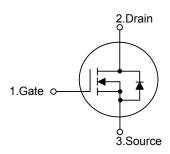
The UTC 14N65K-MT is an N-Channel enhancement mode power MOSFET. The device adopts planar stripe and uses DMOS technology to minimize and provide lower on-state resistance and faster switching speed. It can also withstand high energy pulse under the avalanche and commutation mode conditions.

The UTC 14N65K-MT is ideally suitable for high efficiency switch mode power supply, power factor correction and electronic lamp ballast based on half bridge topology.



- * $R_{DS(ON)}$ < 0.63 Ω @ V_{GS} = 10V, I_{D} = 7 A
- * Fast switching capability
- * Avalanche energy tested
- * Improved dv/dt capability, high ruggedness

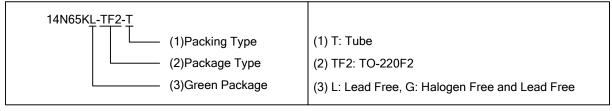
SYMBOL



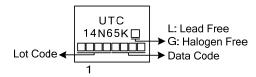
ORDERING INFORMATION

Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
14N65KL-TF2-T	14N65KG-TF2-T	TO-220F2	G	D	S	Tube	

Note: Pin Assignment: G: Gate S: Source D: Drain

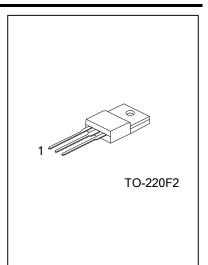


MARKING



www.unisonic.com.tw 1 of 5 QW-R502-B11.d





■ **ABSOLUTE MAXIMUM RATINGS** (T_C = 25°C, unless otherwise specified)

PARAMETER	SYMBOL	RATINGS	UNIT	
Drain-Source Voltage	V_{DSS}	650	V	
Gate-Source Voltage	V_{GSS}	±30	V	
Continuous Drain Current	I _D	14	Α	
Pulsed Drain Current (Note 2)	I _{DM}	48	Α	
Avalanche Current (Note 2)	I _{AR}	14	Α	
Single Pulsed Avalanche Energy (Note 3)	E _{AS}	325	mJ	
Peak Diode Recovery dv/dt (Note 4)	dv/dt	4.5	V/ns	
Power Dissipation (T _C =25°C)	P_{D}	150	W	
Junction Temperature	TJ	+150	°C	
Storage Temperature	T _{STG}	-55~+150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature
- 3. L = 3.31mH, I_{AS} = 14A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 4. $I_{SD} \le 14A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25$ °C

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	62.5	°C/W	
Junction to Case	θ_{JC}	0.83	°C/W	

■ ELECTRICAL CHARACTERISTICS (T_C =25°C, unless otherwise specified)

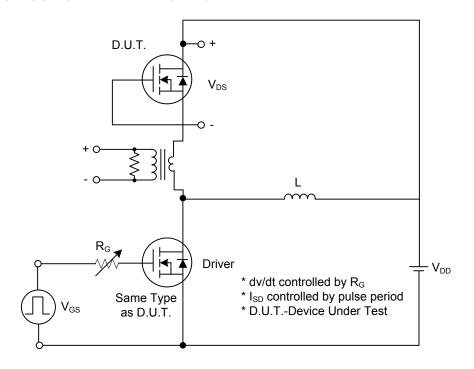
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	$V_{GS} = 0V, I_D = 250 \mu A$	650			V	
Drain-Source Leakage Current	I _{DSS}	$V_{DS} = 650V, V_{GS} = 0V$			10	μΑ	
Cata Cauraa Laakana Cumant	I _{GSS}	$V_{GS} = 30V, V_{DS} = 0V$			100	nA	
Gate-Source Leakage Current		$V_{GS} = -30V, V_{DS} = 0V$			-100	nA	
Breakdown Voltage Temperature Coefficient	$\triangle BV_{DSS}/\triangle T_J$	I _D =250mA,Referenced to 25°C		0.5		V/°C	
ON CHARACTERISTICS	_			-			
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	٧	
Static Drain-Source On-State Resistance	R _{DS(ON)}	$V_{GS} = 10V, I_D = 7A$			0.63	Ω	
DYNAMIC CHARACTERISTICS							
Input Capacitance	C _{ISS}	V _{DS} =25V, V _{GS} =0V, f=1.0MHz		980		pF	
Output Capacitance	Coss			185		pF	
Reverse Transfer Capacitance	C _{RSS}			10		pF	
SWITCHING CHARACTERISTICS							
Turn-On Delay Time	t _{D(ON)}	V_{DS} =30V, I_{D} =0.5A, R_{G} =25 Ω		89		nS	
Turn-On Rise Time	t_R			116		nS	
Turn-Off Delay Time	t _{D(OFF)}	(Note 1, 2)		388		nS	
Turn-Off Fall Time	t _F			145		nS	
Total Gate Charge	Q_G	$V_{GS}=10V, V_{DS}=50V, I_{D}=1.3A$ (Note 1. 2)		47		nC	
Gate-Source Charge	Q_GS			12.2		nC	
Gate-Drain Charge	Q_GD			11.6		nC	
DRAIN-SOURCE DIODE CHARACTERISTIC	S AND MAXIN	MUM RATINGS					
Drain-Source Diode Forward Voltage	V_{SD}	$V_{GS} = 0V, I_{S} = 14A$			1.4	V	
Maximum Continuous Drain-Source Diode					14		
Forward Current	Is				14	Α	
Maximum Pulsed Drain-Source Diode	la				56	Α	
Forward Current	I _{SM}				50	^	

Notes: 1. Pulse Test : Pulse width≤300µs, Duty cycle≤2%

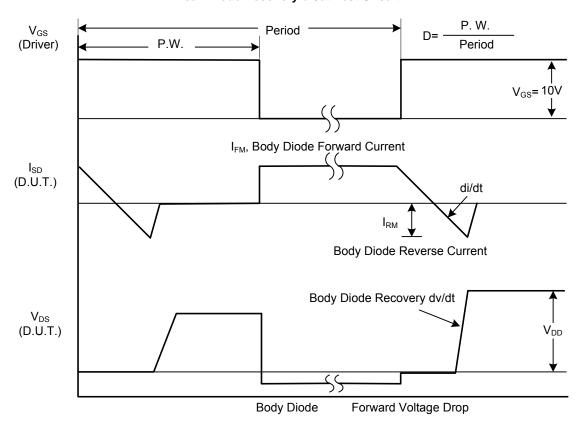
2. Essentially independent of operating ambient temperature



■ TEST CIRCUITS AND WAVEFORMS

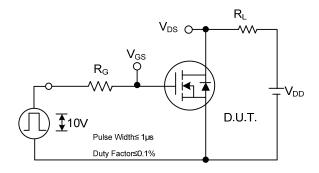


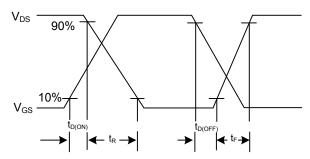
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

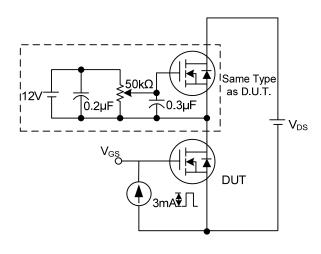
■ TEST CIRCUITS AND WAVEFORMS (Cont.)

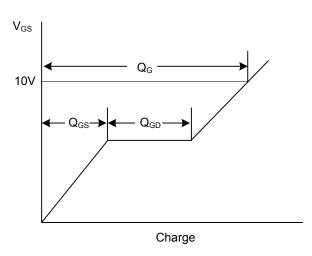




Switching Test Circuit

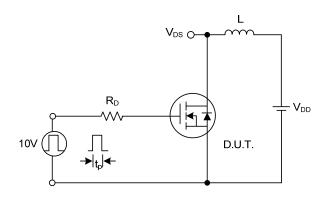
Switching Waveforms

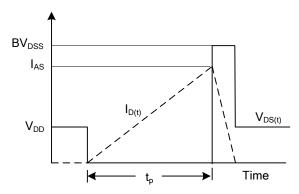




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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